CISPR/TR 16-4-1

Edition 2.0 2009-02

TECHNICAL REPORT

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests

INTERNATIONAL ELECTROTECHNICAL COMMISSION

PRICE CODE XE

ICS 33.100.10; 33.100.20

ISBN 2-8318-1032-4

CONTENTS

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests

FOREWORD

1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
5) IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with an IEC Publication.
6) All users should ensure that they have the latest edition of this publication.
7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a technical report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

CISPR 16-4-1, which is a technical report, has been prepared by CISPR subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

This second edition of CISPR 16-4-1 cancels and replaces the first edition published in 2003, and its Amendments 1 (2004) and 2 (2007). It constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition. The provisions available for application of uncertainties in the determination of the

compliance criterion are explained more generally and a procedure is added for re-testing an approved EUT by another test house.

The text of this technical report is based on the following documents:

Enquiry draft	Report on voting
CISPR/A/818/DTR	CISPR/A/831/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the CISPR 16 series can be found, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

INTRODUCTION

The result of the application of basic considerations (Clauses 4 and 5) in this part to existing or new CISPR standards will lead to proposals to improve and harmonise the uncertainty aspects of those CISPR standards. Such proposals will also be published as reports within this part and will give the background and rationale for improvement of certain CISPR standards. Clause 6 is an example of such a report.

The structure of clauses related to the CISPR standards compliance uncertainty work is depicted in Table 1. Clause 4 deals with the basic considerations of standards compliance uncertainties in emission measurements. Clauses 6, 7 and 8 contain uncertainty considerations related to voltage, absorbing clamp and radiated emission measurements, respectively.

Uncertainty work will also be considered for immunity compliance tests in the future. Clauses 5, 9 and 10 are reserved for this material. SCU (see 3.1.16) considerations of immunity tests differ from the emission SCU considerations in particular points. For instance, in an immunity test, the measurand is often a functional attribute of the EUT and not a specific quantity. This may cause additional specific SCU considerations. Priority has been given to the uncertainty evaluations for emission measurements at this stage of the work.

Table 1 – Structure of clauses related to the subject of standards compliance uncertainty

STANDARDS COMPLIANCE UNCERTAINTY			
Clause 1, 2, and 3: General			
EMISSION			**IMMUNITY**
Clause 4	Basic considerations	Clause 5	Basic considerations
Clause 6	Voltage measurements	Clause 9	Conducted immunity tests
Clause 7	Absorbing clamp measurements	Clause 10	Radiated immunity tests
Clause 8	Radiated emission measurements		

SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests

1 Scope

This part of CISPR 16-4 gives guidance on the treatment of uncertainties to those who are involved in the development or modification of CISPR electromagnetic compatibility (EMC) standards. In addition, this part provides useful background information for those who apply the standards and the uncertainty aspects in practice.

The objectives of this part are to:

a) identify the parameters or sources governing the uncertainty associated with the statement that a given product complies with the requirement specified in a CISPR recommendation. This uncertainty will be called “standards compliance uncertainty” (SCU, see 3.1.16);

b) give guidance on the estimation of the magnitude of the standards compliance uncertainty;

c) give guidance for the implementation of the standards compliance uncertainty into the compliance criterion of a CISPR standardised compliance test.

As such, this part can be considered as a handbook that can be used by standards writers to incorporate and harmonise uncertainty considerations in existing and future CISPR standards. This part also gives guidance to regulatory authorities, accreditation bodies and test engineers to judge the performance quality of an EMC test-laboratory carrying out CISPR standardised compliance tests. The uncertainty considerations given in this part can also be used as guidance when comparing test results (and their uncertainties) obtained by using different alternative test methods.

The uncertainty of a compliance test also relates to the probability of occurrence of an electromagnetic interference (EMI) problem in practice. This aspect is recognized and introduced briefly in this part. However, the problem of relating uncertainties of a compliance test to the occurrence of EMI in practice is not considered within the scope of this part.

The scope of this part is limited to all the relevant uncertainty considerations of a standardized EMC compliance test.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic Compatibility*

IEC 60050-300:2001, *International Electrotechnical Vocabulary (IEV) – Electrical and electronic measurements and measuring instruments – Part 311: General terms relating to measurements – Part 312: General terms relating to electrical measurements – Part 313: Types of electrical measuring instruments – Part 314: Specific terms according to the type of instrument*

IEC 60359:2001, *Electrical and electronic measurement equipment – Expression of performance*

CISPR 16-1-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Conducted disturbances*

CISPR 16-1-3:2004, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-3: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Disturbance power*

CISPR 16-1-4:2007, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-4: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Radiated disturbances*

CISPR 16-1-5:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-5: Radio disturbance and immunity measuring apparatus – Antenna calibration test sites for 30 MHz to 1 000 MHz*

CISPR 16-2-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-2: Methods of measurement of disturbances and immunity – Measurement of disturbance power*
Amendment 1 (2004)
Amendment 2 (2005)

CISPR 16-2-3:2006, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-3: Methods of measurement of disturbances and immunity – Radiated disturbance measurements*

CISPR 16-4-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Uncertainty in EMC measurements*

CISPR/TR 16-4-3:2004, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products*

CISPR 22:2008, *Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement*

ISO/IEC 17025, *General requirements for the competence of testing and calibration laboratories*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement* (GUM:1995)

ISO/IEC Guide 99:2007, *International vocabulary of metrology – Basic and general concepts and associated terms (VIM)*